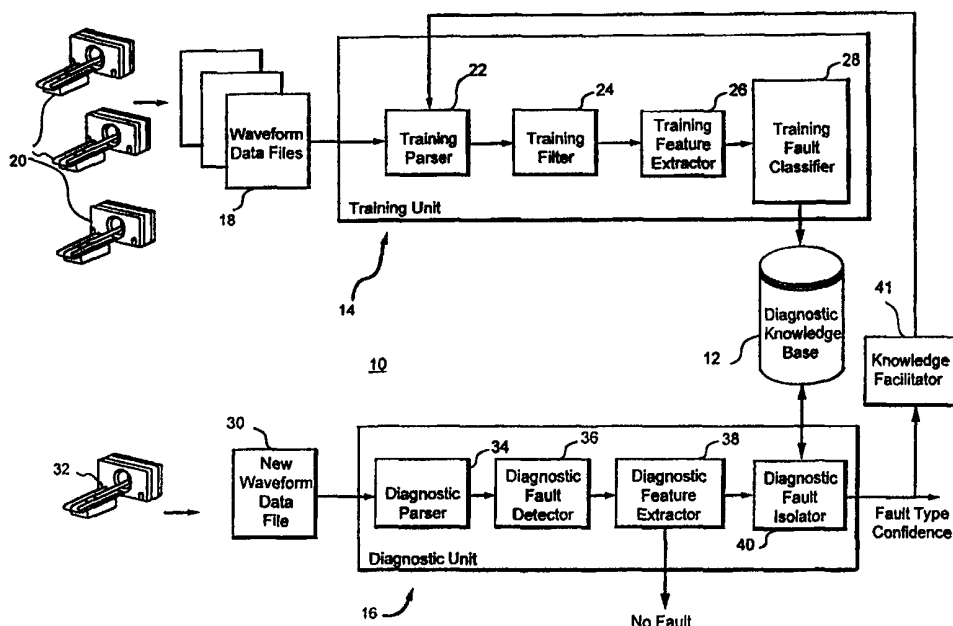




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(54) Title: SYSTEM AND METHOD FOR DIAGNOSING AND VALIDATING A MACHINE USING WAVEFORM DATA



(57) Abstract

The present invention discloses a system (10) and method for diagnosing and validating a machine with waveform data generated therefrom. In this invention, historical waveform data (18) are obtained from machines having known faults (20) along with corresponding actions for repairing the machines and are used to develop fault classification rules. The fault classification rules are stored in a diagnostic knowledge database (12). The database of classification rules are used to diagnose new waveform data (30) from a machine (32) having an unknown fault.

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SYSTEM AND METHOD FOR DIAGNOSING AND VALIDATING A MACHINE USING WAVEFORM DATA

FIELD OF THE INVENTION

5 The present invention relates generally to fault diagnosis and more particularly to using waveform data generated from a machine to provide diagnostics.

BACKGROUND OF THE INVENTION

10 In either an industrial or commercial setting, a malfunctioning machine such as an imaging machine can impair a business severely. Thus, it is essential that a malfunctioning imaging machine be repaired quickly and accurately. Usually, during a malfunction of an imaging machine such as a computed tomography (CT) or a magnetic resonance imaging (MRI) machine, a field engineer is called in to
15 diagnose and repair the machine. Typically, the field engineer will run a system performance test to analyze the image quality or the state of the imaging machine. The system performance test generates waveform data which provides a "signature" of the operation of the imaging machine. The waveform data comprises data sets of various
20 readouts and slice combinations. After the system performance test has been run, the field engineer sends the data sets to a service engineer at a remote location for help in diagnosing the malfunction. The service engineer analyzes the data sets and uses their accumulated experience at solving imaging machine malfunctions to
25 find any symptoms that may point to the fault. The field engineer then tries to correct the problem that may be causing the machine malfunction based on the diagnosis provided by the service engineer.

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If the data sets contain only a small amount of information, then this process will work fairly well. However, if the data sets contains a large amount of imprecise information, as is usually the case for large complex devices, then it is very difficult for the field engineer and the service engineer to quickly diagnose a fault. Therefore, there is a need
5 for a system and method that can quickly diagnose a malfunctioning imaging machine from waveform data sets containing large amount of imprecise information.

SUMMARY OF THE INVENTION

10 In accordance with one embodiment of this invention, there is provided a system and a method for diagnosing a machine from waveform data generated therefrom. In this embodiment, a diagnostic knowledge base contains a plurality of rules for diagnosing faults in a machine and a plurality of corrective actions for repairing the faults. A
15 diagnostic parser removes extraneous data from the waveform data. A diagnostic fault detector categorizes the waveform data as normal and faulty data. A diagnostic feature extractor extracts a plurality of features from the waveform data categorized as faulty data. A diagnostic fault isolator, coupled to the diagnostic feature extractor and
20 the diagnostic knowledge base, isolates a candidate set of faults for the extracted features and identifies root causes most likely responsible for the candidate set of faults.

In accordance with a second embodiment of this invention, there is provided a system and method for performing a validation of
25 waveform data generated from a machine. The waveform data generated from the machine may be either run-time data or stand-by operation data. In this embodiment, a diagnostic knowledge base contains a plurality of rules for diagnosing faults in the machine. A

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diagnostic parser removes extraneous data from the waveform data. A
diagnostic fault detector, coupled to the diagnostic knowledge base
and the diagnostic parser, categorizes the waveform data as normal
and faulty data. A diagnostic feature extractor extracts a plurality of
5 features from the waveform data categorized as normal data.

DESCRIPTION OF THE DRAWINGS

Fig. 1 shows a block diagram of a system for diagnosing an
imaging machine according to this invention;

Fig. 2 shows an example of a data structure for a waveform
10 data file according to this invention;

Fig. 3 shows an example of time series plots for the data sets
represented by the data structure shown in Fig. 2;

Fig. 4 shows a flow chart setting forth the steps performed by
the training parser shown in Fig. 1;

Fig. 5 shows a flow chart setting forth the steps performed by
15 the training filter and the training feature extractor shown in Fig. 1;

Fig. 6 shows a block diagram of a more detailed view of the
training fault classifier shown in Fig. 1;

Fig. 7 shows a flow chart setting forth the processing steps
20 performed by the training fault classifier; and

Fig. 8 shows a flow chart setting forth the fault isolation
processing steps performed by the diagnostic unit shown in Fig. 1.

DETAILED DESCRIPTION OF THE INVENTION

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The diagnosis system of this invention is described with reference to a medical imaging device such as a CT or a MRI machine. Although this invention is described with reference to a medical imaging device, the diagnosis system can be used in conjunction with
5 any device (chemical, mechanical, electronic, microprocessor controlled) which generates waveform outputs. Fig. 1 shows a block diagram of a system 10 for diagnosing an imaging machine according to this invention. The diagnosis system 10 includes a diagnostic knowledge base 12 containing a plurality of rules for diagnosing faults
10 in an imaging machine, a training unit 14, and a diagnostic unit 16. The training unit 14 obtains a plurality of sets of waveform data files 18 taken from a plurality of imaging machines 20. The training unit 14 includes a training parser 22 for removing extraneous data from each of the sets of waveform data, a training filter 24 for categorizing each of
15 the sets of waveform data as normal and faulty data, and a training feature extractor 26 for extracting a plurality of features from each of the sets of waveform data categorized as faulty data, and a training fault classifier 28 for developing a plurality of steps that classify the extracted features into a fault characterization and providing the steps
20 to the diagnostic knowledge base 12.

The diagnostic unit 16 obtains a new waveform data file 30 from an imaging machine 32. The diagnostic unit 16 includes a diagnostic parser 34 for removing extraneous data from the new waveform data, a diagnostic fault detector 36 for categorizing the new waveform data
25 as normal and faulty data, a diagnostic feature extractor 38 for extracting a plurality of features from the new waveform data categorized as faulty data, and a diagnostic fault isolator 40 coupled to the diagnostic knowledge base 12, for isolating a candidate set of

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faults for the extracted features and identifying root causes most likely responsible for the candidate set. Both the training unit 14 and the diagnostic unit 16 are embedded in a computer such as a workstation. However other types of computers can be used such as a mainframe, a minicomputer, a microcomputer, or a supercomputer. The algorithms performed in both the training unit 14 and the diagnostic unit 16 are programmed in C++, JAVA, and MATLAB, but other languages may be used.

The candidate set of faults generated from the diagnostic unit 16 are presented to a knowledge facilitator 41, which in this invention is a service engineer. The service engineer examines the candidate set and determines if the fault for the MRI machine 32 has been correctly identified. If the fault has not been correctly identified, then the service engineer identifies the correct fault type and inputs the new waveform data and fault type information into the training unit 14 so that it can be used to identify future faults of a similar nature. In particular, the waveform data and fault type information are inputted to the training parser 22 for parsing, the training filter 24, the training feature extractor 26 and the training fault classifier 28.

The plurality of sets of waveform data files 18 generated from the plurality of MRI machines 20 are obtained from imaging phantoms. Each of the waveform data files 18 have known faults associated therewith. An illustrative but not exhaustive list of some of the known faults are inadequately compensated long time constant eddy currents, environmental magnetic field disturbances, magnitude and constant phase spikes caused by a body preamplifier, spikes caused by a defective IPG, high vibrations caused by rotating machinery on the floor above or below the magnet, failures caused by a defective Y-axis

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GRAM, and failures caused by a loose dynamic disable box RF connectors on the body coil.

The two areas of the phantoms that are scanned are the head and the body. A fast spin echo (FSE) test and a fast gradient test (FGRE) are run for both the head and the body. The FSE test has a high RF duty cycle which makes it more sensitive to RF related problems, while the FGRE test which stresses primarily the gradient drivers, is more sensitive to gradient related problems. These tests are then run at multiple locations to generate a complete data set. A complete data set comprises 90 data sets. The FGRE data contains 256 data points while the FSE data contains 512 data points. An example of a data structure 42 for a waveform data file 18 according to this invention is shown in Fig. 2. The data structure 42 is divided into two categories the head and the body. As mentioned above, for both the head and the body, a FSE and a FGRE test is run at various locations. For example, as shown in Fig. 2, a body FSE data set is taken at XY (X slice, Y readout) at L78 (left 78), iso (isocenter), and R78(right 78). Other acronyms listed in Fig. 2 are P (posterior), A (anterior), I (inferior), and S (superior). The data acquired at the various locations for both the head FSE and FGRE and body FSE and FGRE are representative of three variables $x_1(t_j)$, $x_2(t_j)$, $x_3(t_j)$. The $x_1(t_j)$ variable is representative of the echo shift, the $x_2(t_j)$ variable is representative of the constant phase drift, and the $x_3(t_j)$ variable is representative of the magnitude drift, wherein t_j indicates the j^{th} time. The three variables $x_1(t_j)$, $x_2(t_j)$, $x_3(t_j)$ are sampled over time to create three time series plots 44 of n points. An example of a time series plots 44 for the head FSE, head FGRE, body FSE, and body FGRE are shown in Fig. 3.

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Each waveform data file 18 is inputted into the training unit 14. The training parser 22 then extracts data from each file. A flow chart setting forth the steps performed by the training parser 22 is set forth in Fig. 4. The training parser begins by obtaining one of the waveform data files at 46 for each historical case. The header information (i.e., system hardware, software version, site of the MRI, type of MRI, manufacturing date, date stamp, etc.) is retrieved and saved into an information file at 48. For each block of data in the file, the waveform data is extracted at 50 and saved into a parsed file at 52. If all of the waveform data files have been parsed then this process ends.

After each waveform data file 18 has been parsed for data and information, the files are then applied to the training filter 24 for preprocessing and the training feature extractor 26 for further processing. Fig. 5 shows a flow chart setting forth the steps performed by the training filter 24 and the training feature extractor 26. In this invention the training filter is a gross filter and a fine filter. At 56, the training filter obtains a waveform data file from the training parser. For each file, the training filter performs a time domain analysis, a frequency domain analysis, and a wavelet analysis at 58. For the time domain analysis, time series data is used to compute peak-to-peak values in a graph, the area under a curve (integral) in the graph, and the slope of a curve (derivative). The frequency domain analysis uses the Fast Fourier Transform (FFT) to decompose a time-series plot of data into different frequency components for analyzing relative magnitudes. The wavelet analysis is achieved by using a discrete wavelet transform (DWT) which is the counterpart of the FFT. Like the FFT, the DWT requires that the number of samples to be a power of two. The DWT analyzes the signal at different time scales or

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resolutions. With a large window, "gross" features can be noticed, while with a small window, "small" features like spikes can be noticed. In the DWT, the signal is approximated by a finite sum of coefficients W_i that multiply scaled versions of the mother wavelet (the original basis function).

The time domain analysis, frequency domain analysis, and wavelet analysis are used to extract features at 60. If desired, a data visualizer routine may be applied to the data that remains after performing the time domain analysis, frequency domain analysis, and wavelet analysis in order to allow a service engineer to visualize all of the time series plots for the head FSE, head FGRE, body FSE, and body FGRE. The features that are extracted from the time domain analysis are:

the minimum of the time series which is defined as:

15

$$v_{1,i} = \min_{j=1}^n x_i(t_j); \quad (1)$$

the maximum value of the time series which is defined as:

20

$$v_{2,i} = \max_{j=1}^n x_i(t_j); \quad (2)$$

the peak-to-peak distance of the time series which is defined as:

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$$v_{3,i} = v_{2,i} - v_{1,i}; \quad (3)$$

the time series average which is defined as:

5

$$v_{4,i} = \frac{\sum_{j=1}^n x_i(t_j)}{n}; \quad (4)$$

the standard deviation of the time series which is defined as:

$$10 \quad v_{5,i} = \sqrt{\frac{\sum_{j=1}^n (x_i(t_j) - v_{4,i})^2}{n-1}}; \quad (5)$$

the minimum absolute value of the time series during the first 64 samples which is defined as:

$$15 \quad v_{6,i} = \min_{j=1}^{64} |x_i(t_j)|; \quad (6)$$

the time of minimum value for the first 64 samples which is defined as:

- 10 -

$$v_{7,i} = j_{\min}, \quad \text{wherein } x_i(t_{j\min}) = v_{6,i}; \quad (7)$$

the sign of the minimum value for the first 64 samples which is defined
5 as:

$$v_{8,i} = \text{sign}\{x_i(t_{j\min})\}, \quad \text{wherein } x_i(t_{j\min}) = v_{6,i}; \quad (8)$$

the maximum absolute value of the time series during the first 64
10 sample which is defined as:

$$v_{9,i} = \max_{j=1}^{64} |x_i(t_j)|; \quad (9)$$

the time of the maximum value for the first 64 samples which is defined
15 as:

$$v_{10,i} = j_{\max}, \quad \text{wherein } x_i(t_{j\max}) = v_{9,i}; \quad (10)$$

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the sign of the maximum value for the first 64 samples which is defined as:

$$v_{11,i} = \text{sign}\{x_i(t_{j \max})\} \text{ where } x_i(t_{j \max}) = v_{9,i}; \text{ and} \quad (11)$$

5

the slope of the line segment approximating the time series derivative during the first 64 samples which is defined as:

$$v_{12,i} = \frac{(x_i(t_{64}) - x_i(t_1))}{63} \quad (12)$$

10

The features that are extracted from the frequency domain analysis are:

the maximum amplitude of the power spectrum which is defined as:

$$15 \quad v_{13,i} = \max_{j=1}^n A_j, \quad (13)$$

wherein A_j is the j^{th} amplitude of the FFT of $x_i(t_j)$;

the frequency at which the maximum amplitude occurs which is defined as:

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$$v_{14,i} = \max_{j=1}^n F_j, \quad (14)$$

wherein F_j is the j^{th} frequency component of the FFT of $x_i(t_j)$; and

5 the total power which is defined as:

$$v_{15,i} = \sum_{j=1}^n C_j^2, \quad (15)$$

wherein C_j is the j^{th} coefficient of the FFT of $x_i(t_j)$.

The features that are extracted from the wavelet analysis are
 10 determined after all of the coefficients of the wavelet transform W_i have
 been computed. The first wavelet feature is the maximum absolute
 value among all spikes. This feature is applied to the points in the
 scatter plot of the last two wavelet coefficients ($W_{n,i}$, $W_{n-1,i}$). Since
 these coefficients are good indicators of spikes, the energy contained
 15 in a spike is not considered to be noticeable on the full-length time
 window used by the mother wavelet or by an FFT. However, the
 energy contained in the spike can be considerable and easy to detect
 once it is compared with the rest of the signal in a very reduced time
 window. In order to determine the maximum absolute value among all
 20 spikes, the centroid coordinates of the clustered data must first be
 computed. The centroid coordinates of the clustered data is defined
 as:

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$$(C_k, C_{k-1}) = \left(\frac{\sum_{j=1}^n W_k^j}{n}, \frac{\sum_{j=1}^n W_{k-1}^j}{n} \right)$$

- Next, all the outliers (i.e., points that are considerably far from the centroid of clustered data) in the scatter plot are identified. The outliers are identified as:

$$d_{1,i} = \sqrt{(W_{k,i} - C_k)^2 + (W_{k-1,i} - C_{k-1})^2}$$

- Next, three standard deviation is used as the threshold for the outliers. Alternatively, filtering may be used to remove some noise for the weak signals around zero. Finally, the outlier that is the furthest away from the centroid, i.e., is considered to be the strongest spike which is defined as:

15

$$v_{16,i} = \max_j d_{1,i}^j \quad (16)$$

The next wavelet feature that is determined is the sign of the strongest spike which is defined as:

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$$v_{17,i} = \text{sign}\{W_{k,j_{\max}}\}, \quad (17)$$

wherein $\sqrt{(W_{k,j_{\max}} - C_k)^2 + (W_{k-1,j_{\max}} - C_{k-1})^2} = v_{16,i}$

- 5 Another wavelet feature that is determined is the time at which the strongest spike occurs which is defined as:

$$v_{18,i} = j_{\max} \quad (18)$$

wherein $\sqrt{(W_{k,j_{\max}} - C_k)^2 + (W_{k-1,j_{\max}} - C_{k-1})^2} = v_{16,i}$

10

Still another wavelet feature that is determined is the number of spikes which is defined as:

$$v_{19,i} = \sum_{j=1}^k d_{1,j}, \quad (19)$$

- 15 wherein $d_{1,j}$ is greater than 3 standard deviation.

Referring back to Fig. 5, after the features have been extracted, then a vector is formed for a file at 62 for the time domain features,

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frequency domain features, and the wavelet features. Next, the vectors are combined at 64 to yield a feature vector. The feature vector represents in a feature space, the time-series values of each of the variables $x_1(t_j)$, $x_2(t_j)$, $x_3(t_j)$. After all of the features have been
5 extracted, then the feature vectors are placed into a feature matrix at 66. In this invention, the feature matrix would be a 90 x 19 matrix. If it is determined at 68 that there are more files, then steps 56-66 are repeated until features have been extracted for all files.

After the features have been extracted from all of the waveform
10 data files, the features are then applied to the training fault classifier 28 where the plurality of rules are developed. The rules are used to classify the feature matrices into a particular fault characterization. Fig. 6 shows a block diagram of the training fault classifier 28 in more detail. The training fault classifier comprises an expert system
15 having a rule base 72 and a rule selector 74 for selecting the most applicable steps from the rule base. The rule base 72 comprises a FSE rule set 76 and a FGRE rule set 78. Both the FSE and FGRE rule set are based on an IF-THEN rules defined for the following example faults:

20

f_1 : Inadequately compensated long time constant eddy currents;

f_2 : Environmental magnetic field disturbances;

f_3 : Magnitude and constant phase spikes;

f_4 : Spikes caused by a defective IPG;

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f_5 : High vibration caused by rotating machinery on the floor;

f_6 : Failures caused by a defective Y-axis GRAM; and

f_7 : Failures caused by a loose dynamic disable box RF connectors.

- 5 This invention is not limited to these faults and other possible faults may be a RF receive fault, a RF transmit fault, a RF receive and transmit fault, a shim fault, a S-V magnet signature fault, a steady state disturbance (i.e., vibration), a gradient axis fault, a magnet disturbance, a steady state disturbance (i.e., cold heads and magnetic anomaly, a
- 10 transient vibration, a SNR having a low signal, and a SNR having high noise.

In this invention, the faults f_1 - f_7 , are identified by using the following rules:

15 $R_{1A} \rightarrow f_1$ applicable for slice Y, readout Z;

$R_{1B} \rightarrow f_1$ applicable for slice Z, readout X;

$R_{2A} \rightarrow f_2$ applicable for slice X, readout Y;

$R_{2B} \rightarrow f_2$ applicable for slice Y, readout Z;

$R_{3A} \rightarrow f_3$ applicable for FSE;

20 $R_{3B} \rightarrow f_3$ applicable for FGRE;

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$R_{4A} \rightarrow f_4$ applicable for FSE;

$R_{4B} \rightarrow f_4$ applicable for FGRE;

$R_5 \rightarrow f_5$ applicable for FSE;

$R_{6A} \rightarrow f_6$ applicable for FSE;

5 $R_{6B} \rightarrow f_6$ applicable for FGRE;

$R_{7A} \rightarrow f_7$ applicable for FSE; and

$R_{7B} \rightarrow f_7$ applicable for FGRE

The linguistic rules for R_{1A} - R_{7B} are as follows:

10

R_{1A} : regardless of location, x_1 shows a discharge in the first 64 samples, while x_2 and x_3 are normal;

R_{1B} : regardless of location (except for ISO), x_2 shows a discharge in the first 64 samples, while x_1 and x_3 are normal;

15 R_{2A} : regardless of location, x_2 shows large excursions, while x_1 and x_3 are normal;

R_{2B} : regardless of location, x_2 shows very large excursions, while x_1 and x_3 are almost normal;

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R_{3A}: x_2 and x_3 show only one spike, of opposite sign, at about the same time, while x_1 is normal;

R_{3B}: x_2 and x_3 show only one spike, of opposite sign, at about the same time, while x_1 is normal;

- 5 *R_{4A}*: x_1 , x_2 and x_3 show two spikes, one spike that propagates a second time, wherein the spikes occur at about the same time across all three variables;

- 10 *R_{4B}*: x_1 , x_2 and x_3 show two spikes, one spike that propagates a second time, wherein the spikes occur at about the same time across all three variables;

R₅: x_2 shows a large number of spikes in both directions, while x_1 and x_3 are normal;

- 15 *R_{6A}*: except for the ISO location, x_2 shows repeated spikes, all in the same direction, furthermore the spikes in x_2 are of opposite direction on opposite sides of the isocenter; meanwhile, x_1 is normal and x_3 is assumed to be equally normal, although it is not available in the data sets;

R_{6B}: except for the ISO location, x_1 shows repeated spikes, all in the same direction, while x_2 and x_3 is normal;

- 20 *R_{7A}*: except for the ISO location, x_2 and x_3 show a large number of spikes, in the opposite direction, while x_1 shows numerous small spikes; and

R_{7B}: large spikes in x_2 .

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Each of the above rules have a conjunction of predicates defining the set of conditions that must be satisfied to determine if the rule is true given the data. The rules are satisfied when all of its terms
5 have been fulfilled, i.e., when all underlying constraints have been satisfied by the waveform data. In this invention, some of the terms in the rules R_{1A} - R_{7B} have the following meaning:

discharge: is the derivative in the first 64 samples $[v_{9,i}]$ coupled
10 with the minimum and maximum values in the same first 64 samples $[v_{6,i}, v_{7,i}]$;

normal: means that the total power $[v_{12,i}]$ is small and there is no spikes of large magnitude;

almost normal: means that there is noise on top of a normal
15 signal;

large excursion: means that the range is greater than five or six standard deviations (2.5-3.0 sigmas on each side of the mean);

very large excursion: means that the range is greater than seven or eight standard deviations (3.5-4.0 sigmas on each side of the
20 mean)

only one spike: is obtained from the presence of a spike via $v_{16,i}$ and the number of spikes $v_{19,i}=1$;

spikes of opposite sign: are obtained by applying $v_{17,i}$ to the feature vector of x_i and x_j and verifying that the two signs are opposite;

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about the same time: is when two events occur within a short period of time (generally in 3 to 5 time steps); this is determined by applying $v_{18,i}$ to the two variables x_i and x_j and verifying that the time of the spike is within this small time window;

- 5 *two spikes:* is obtained by detecting the presence of a spike via $P_{1,i}$ and when the number of spikes $v_{19,i}=2$;

repeated spikes: are two successive spikes with similar magnitude within a finite period of time;

- 10 *numerous small spikes:* are a number of points with small magnitude are more than 3 sigma away from the centroid of the clustered data in the scatter plot of the last two wavelet coefficients; and

- 15 *large number of spikes:* are a number of points with relative large magnitude which are far away from the centroid of the clustered data in the scatter plot of the last two wavelet coefficients.

20 The rules $R_{1A}-R_{7B}$ are then reformulated into IF-THEN rules and stored in the FSE rule set 76 and the FGRE rule set 78. For example, R_{3A} for the FSE mode would be formulated as IF x_2 and x_3 show only one spike, of opposite sign, at about the same time, while x_1 is normal, THEN fault is f_3 . The other rules would be formulated in a similar manner.

25 Referring back to Fig. 6, after the rule sets have been developed, a fusion module 80 uses the rules along with information such as the extracted feature matrices, the FSE, the FGRE, and the

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slice data to determine the fault type. In addition, the fusion module 80 considers other factors such as the amount of data available, the number of locations that the data was taken at, multiple slice locations provides a confidence value that is indicative of the confidence in
5 declaring the fault type. Essentially, the completeness of the data is a major factor in determining the confidence in the fault classification and characterization. For instance, if there is only body FSE data and body FGRE data, then the confidence value would be 0.5. After the fault types and confidence values are assigned, then these values can be
10 used by a service engineer to identify the root causes most likely responsible for the faults by a fault type and confidence value routine. In addition, the service engineer can use this information to determine the recommended fixes for correcting the faults.

Fig. 7 shows a flow chart setting forth the processing steps
15 performed by the training fault classifier 28. The processing steps begin at 82 where all of the feature matrices are obtained from the training feature extractor. Each feature matrix is then examined at 84. The most discriminate features and variables in the matrix are then identified at 86. In particular, the feature vectors are examined to
20 determine if a particular variable exceeds a predetermined threshold. If it is determined that there are more feature matrices at 88, then the next feature matrix is retrieved at 90 and examined at 86 to determine the most discriminate feature vector and variable. This process continues until all of the feature matrices have been examined. The
25 discriminate feature vectors and variables are then used to formulate the FSE rule set and the FGRE rule set at 92. In order to ensure that the rule sets will work on new set of waveform data, the rules are

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tested at 94. After the rule sets have been tested, then the rules are sent to the diagnostic knowledge base at 96.

After the rule sets have been sent to the diagnostic knowledge base 12, then the diagnostic unit 16 is ready to be used to diagnose
5 new waveform data from MRI machines having unknown faults. Referring back to Fig. 1, the diagnostic unit 16 receives the new waveform data file 30 generated from the MRI machine 32 experiencing an unknown fault. The new waveform data file 30 is inputted to the diagnostic unit 16 at the diagnostic parser 34 by either a
10 service engineer or by a remote dial-in connection by a field engineer.

The steps performed by the diagnostic parser 34 are substantially the same as the steps for the training parser 22 which are set forth in Fig. 4. Essentially, the diagnostic parser 34 extracts blocks of data from the new waveform data file 30 and saves it in a file for
15 each slice-readout and location data set. In addition, an information file is created for the header which contains information about the system hardware, software version, magnet type, site information, date stamp, and other relevant information. After the new waveform data file 30 has been parsed, the file is then applied to the diagnostic fault
20 detector 36 for preprocessing. Like, the training filter 24, the diagnostic fault detector 36 is a gross filter and fine filter that categorizes the new waveform data as normal and faulty data. In particular, a time domain analysis, a frequency domain analysis, and a wavelet analysis are performed on each block of data. In addition to filtering, a data
25 visualizer routine may be applied to the parsed data file in order to allow a field/service engineer to visualize all of the time series plots for the head FSE, head FGRE, body FSE, and body FGRE.

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After the time domain analysis, a frequency domain analysis, and a wavelet analysis have been performed, the diagnostic feature extractor 38 extracts a plurality of feature vectors for each block and puts the feature vectors into a feature matrix. In instances where the
5 diagnostic fault detector categorizes the waveform data as normal, then the diagnostic unit 16 outputs that the operation of the machine has no fault. This aspect of the invention is well suited for performing a validation of the waveform data that is generated in either a run-time mode or stand-by operation mode. However, for faulty data, the
10 extracted feature matrix is then applied to the diagnostic fault isolator 40 which operates in conjunction with the diagnostic knowledge base 12 to isolate a candidate set of faults. In this invention, the diagnostic fault isolator 40 is a rule-based reasoning expert system. Like the training fault classifier, the diagnostic fault isolator 40 comprises an
15 expert system having a rule base (FSE rule set and a FGRE rule set) and a rule selector for selecting the most applicable rules from the rule base. Alternatively, other types of artificial reasoning techniques may be used such as case based reasoning, inference classification (i.e., linear classifiers, neural networks, rule based classifiers, and distance
20 classifiers), and fuzzy reasoning.

Fig. 8 shows a flow chart setting forth the fault isolation processing steps performed by the diagnostic fault isolator 40. The processing steps begin at 98 where the feature matrix is obtained from the diagnostic feature extractor 38. The feature matrix is then
25 examined at 100. The most discriminate features and variables in the matrix are then identified at 102. In particular, the feature vector is examined to determine if a particular variable exceeds a predetermined threshold. Next, the rule set in the diagnostic

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knowledge base is applied to the feature matrix at 104. The rules are applied in accordance with the features that were identified as most discriminate and are used to generate a candidate set of faults at 106 that may be responsible for the fault associated with the MRI machine
5 32.

The candidate set of faults are then presented to a service engineer along with a respective confidence value indicating a belief that the fault is most likely responsible for the fault. The service engineer then examines the candidate set and determines if the fault
10 for the MRI machine 32 has been correctly identified. If the fault has not been correctly identified, then the service engineer identifies the correct fault type and inputs the new waveform data into the training unit 14 for identifying future faults. In particular, the waveform data and fault type information are inputted to the training parser 22 for
15 parsing, the training filter 24, the training feature extractor 26 and the training fault classifier 28.

It is therefore apparent that there has been provided in accordance with the present invention, a system and method for diagnosing an imaging machine using waveform data that fully satisfy
20 the aims and advantages and objectives hereinbefore set forth. The invention has been described with reference to several embodiments, however, it will be appreciated that variations and modifications can be effected by a person of ordinary skill in the art without departing from the scope of the invention.

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CLAIMS:

1. A system for diagnosing a machine from waveform data generated therefrom, comprising:

5 a diagnostic knowledge base containing a plurality of rules for diagnosing faults in a machine and a plurality of corrective actions for repairing the faults;

a diagnostic parser for removing extraneous data from the waveform data;

10 a diagnostic fault detector for categorizing the waveform data as normal and faulty data;

a diagnostic feature extractor for extracting a plurality of features from the waveform data categorized as faulty data; and

15 a diagnostic fault isolator coupled to the diagnostic feature extractor and the diagnostic knowledge base for isolating a candidate set of faults for the extracted features and identifying root causes most likely responsible for the candidate set of faults.

2. The system according to claim 1, wherein the waveform data comprises a plurality of time series plots.

3. The system according to claim 1, wherein the diagnostic fault detector comprises a gross filter and a fine filter.

4. The system according to claim 1, wherein the diagnostic feature extractor uses a time domain analysis, a frequency domain analysis, and a wavelet analysis.

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5. The system according to claim 1, wherein the diagnostic fault isolator is a rule-based reasoning expert system.

6. The system according to claim 1, wherein the diagnostic fault isolator further comprises means for assigning a measure of confidence to each of the identified candidate set of faults, each measure of confidence indicating a belief that the fault is the most
5 likely cause thereof.

7. The system according to claim 1, further comprising a training unit coupled to the diagnostic knowledge base, the training unit comprising:

means for obtaining a plurality of sets of waveform data taken
5 from a plurality of machines, each of the sets of waveform data having known faults associated therewith and a corresponding corrective action for repairing the faults;

a training parser for removing extraneous data from each of the sets of waveform data;

10 a training filter for categorizing each of the sets of waveform data as normal and faulty data;

a training feature extractor for extracting a plurality of features from each of the sets of waveform data categorized as faulty data; and

15 a training fault classifier for developing a plurality of rules that classify the feature extractions into a fault characterization and providing the plurality of rules to the diagnostic knowledge base.

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8. The system according to claim 7, wherein the plurality of sets of waveform data comprise a plurality of time series plots.

9. The system according to claim 7, wherein the training filter comprises a gross filter and a fine filter.

10. The system according to claim 7, wherein the training feature extractor uses a time domain analysis, a frequency domain analysis, and a wavelet analysis.

11. The system according to claim 7, wherein the training fault classifier is a rule-based reasoning expert system.

12. The system according to claim 1, wherein the machine is a magnetic resonance imaging machine.

13. A method for diagnosing a machine having an unknown fault, comprising the steps of:

obtaining a plurality of rules for diagnosing faults and a plurality of corrective actions for repairing the faults;

5 receiving new waveform data from the machine;

removing extraneous data from the new waveform data;

categorizing the new waveform data as normal and faulty data;

extracting a plurality of features from the new waveform data categorized as faulty data;

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10 isolating a candidate set of faults for the extracted features and identifying root causes most likely responsible for the candidate set of faults.

14. The method according to claim 13, wherein the new waveform data comprises a plurality of time series plots.

15. The method according to claim 13, wherein the step of categorizing the new waveform data as normal and faulty data comprises using a gross filter and a fine filter.

16. The method according to claim 13, wherein the step of extracting a plurality of features comprises using a time domain analysis, a frequency domain analysis, and a wavelet analysis.

17. The method according to claim 13, wherein the step of isolating a candidate set of faults and identifying root causes comprises using a rule-based reasoning expert system.

18. The method according to claim 13, further comprising the step of assigning a measure of confidence to each of the identified candidate set of faults, each measure of confidence indicating a belief that the fault is the most likely cause thereof.

19. The method according to claim 13, wherein the step of obtaining the plurality of rules for diagnosing faults and the plurality of corrective actions for repairing the faults comprises the steps of:

5 obtaining a plurality of sets of waveform data taken from a plurality of machines, each of the sets of waveform data having known faults associated therewith;

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removing extraneous data from each of the sets of waveform data;

10 categorizing each of the sets of waveform data as normal and faulty data;

extracting a plurality of features from each of the sets of waveform data categorized as faulty data; and

developing a plurality of rules that classify the feature extractions into a fault characterization.

20. The method according to claim 19, wherein the plurality of sets of waveform data comprise a plurality of time series plots.

21. The method according to claim 19, wherein the step of categorizing each of the sets of waveform data as normal and faulty data comprises using a gross filter and a fine filter.

22. The method according to claim 19, wherein the step of extracting a plurality of features from each of the sets of waveform data comprises using a time domain analysis, a frequency domain analysis, and a wavelet analysis.

23. The method according to claim 13, wherein the machine is a magnetic resonance imaging machine.

24. A system for performing a validation of waveform data generated from a machine, comprising:

a diagnostic knowledge base containing a plurality of rules for diagnosing faults in the machine;

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- 5 a diagnostic parser for removing extraneous data from the waveform data;
- a diagnostic fault detector, coupled to the diagnostic parser and the diagnostic knowledge base, for categorizing the waveform data as normal and faulty data; and
- 10 a diagnostic feature extractor for extracting a plurality of features from the waveform data categorized as normal data.
25. The system according to claim 24, wherein the waveform data comprises a plurality of time series plots.
26. The system according to claim 24, wherein the diagnostic fault detector comprises a gross filter and a fine filter.
27. The system according to claim 24, wherein the diagnostic feature extractor uses a time domain analysis, a frequency domain analysis, and a wavelet analysis.
28. The system according to claim 24, wherein the machine is a magnetic resonance imaging machine.
29. A method for performing a validation of waveform data generated from a machine, comprising the steps of:
- obtaining a plurality of rules for diagnosing faults;
- receiving new waveform data from the machine;
- 5 removing extraneous data from the new waveform data;
- categorizing the new waveform data as normal and faulty data with the plurality of rules; and

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extracting a plurality of features from the new waveform data categorized as normal data.

30. The method according to claim 29, wherein the new waveform data comprises a plurality of time series plots.

31. The method according to claim 29, wherein the step of categorizing the new waveform data as normal and faulty data comprises using a gross filter and a fine filter.

32. The method according to claim 29, wherein the step of extracting a plurality of features comprises using a time domain analysis, a frequency domain analysis, and a wavelet analysis.

33. The method according to claim 29, wherein the machine is a magnetic resonance imaging machine.

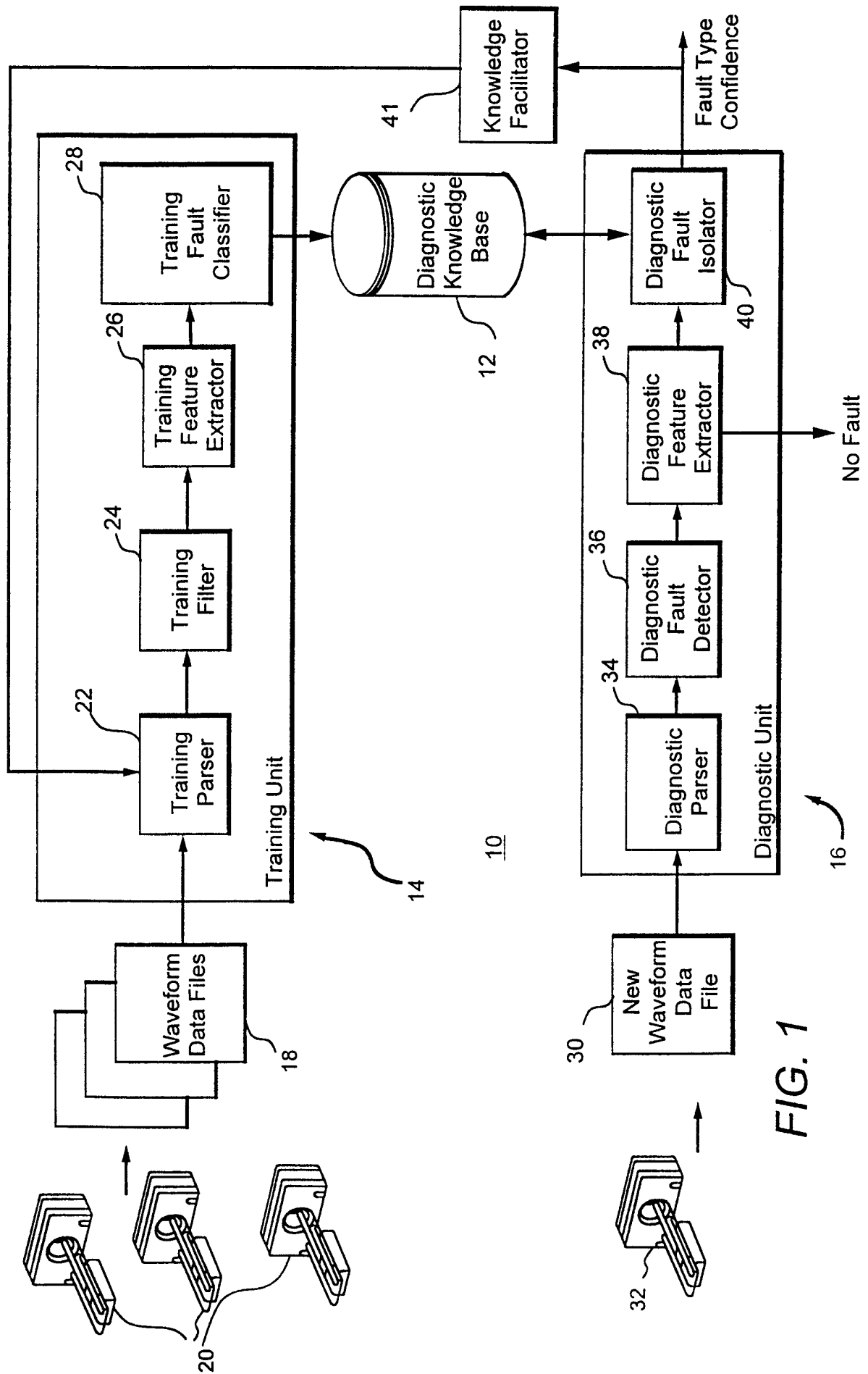


FIG. 1

HEAD	FSE	XY	L33		R33
		YZ	P33		A33
		ZX	I33		S33
	FGRE	XY	L33		R33
		YZ	P33		A33
		ZX	I33		S33
BODY	FSE	XY	L78	iso	R78
		YZ	P78	iso	A78
		ZX	I1378	iso	I1222
	FGRE	XY	L78	iso	R78
		YZ	P78	iso	A78
		ZX	I1378	iso	I1222



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FIG. 2

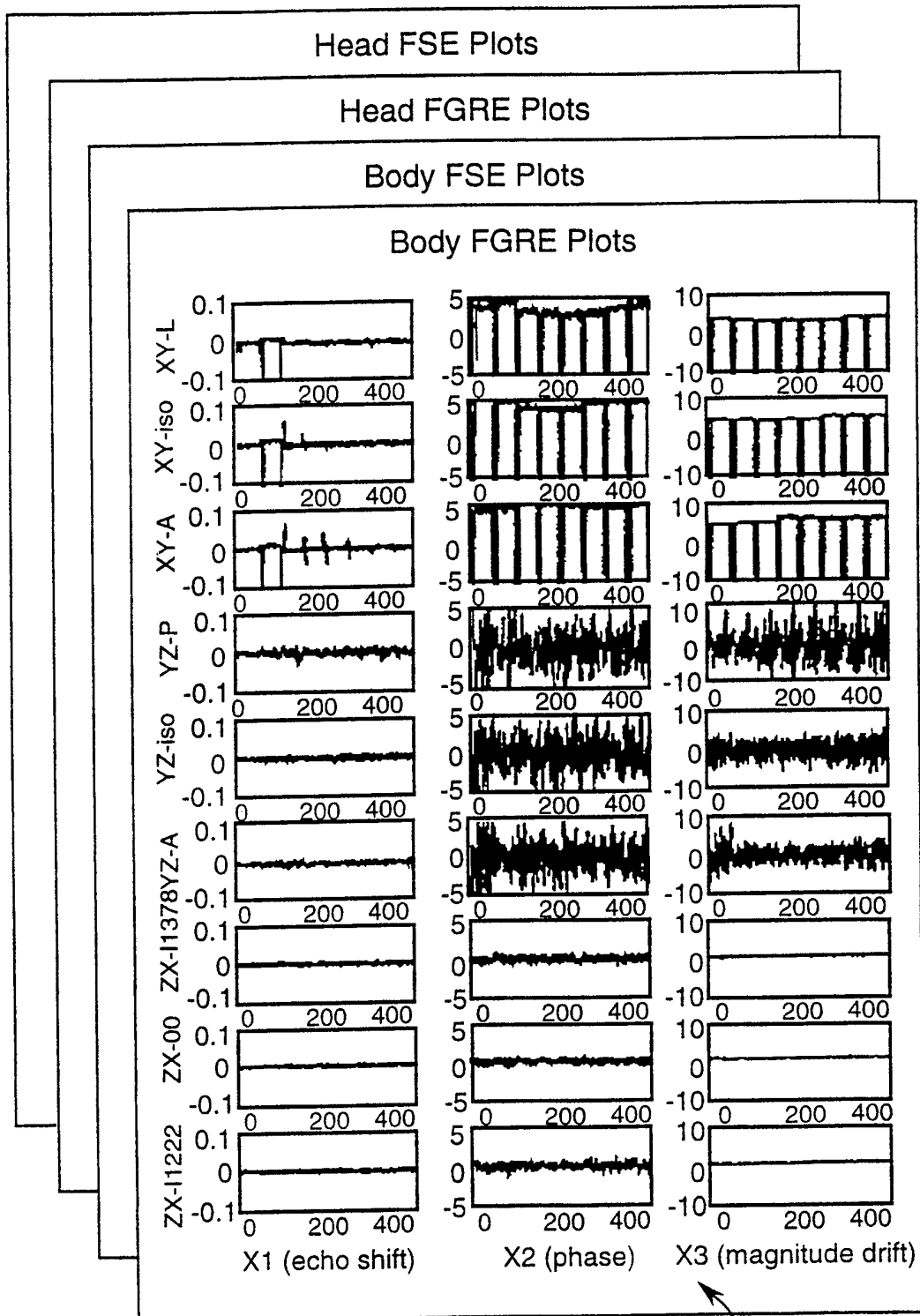
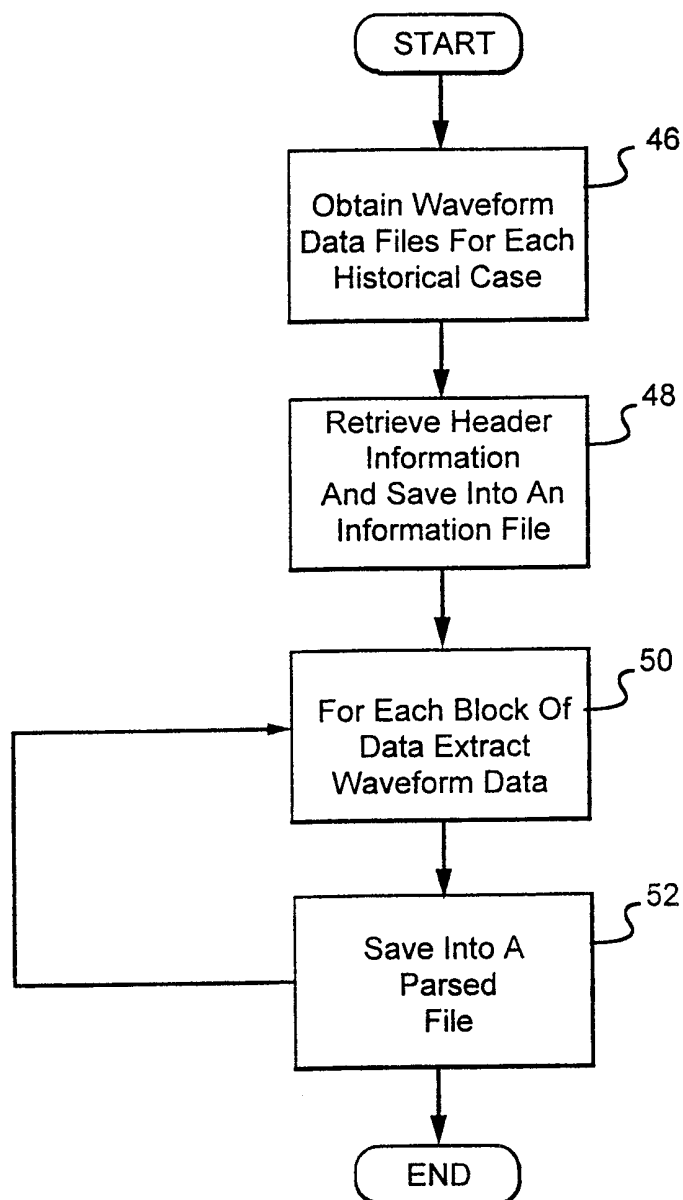


FIG. 3

*FIG. 4*

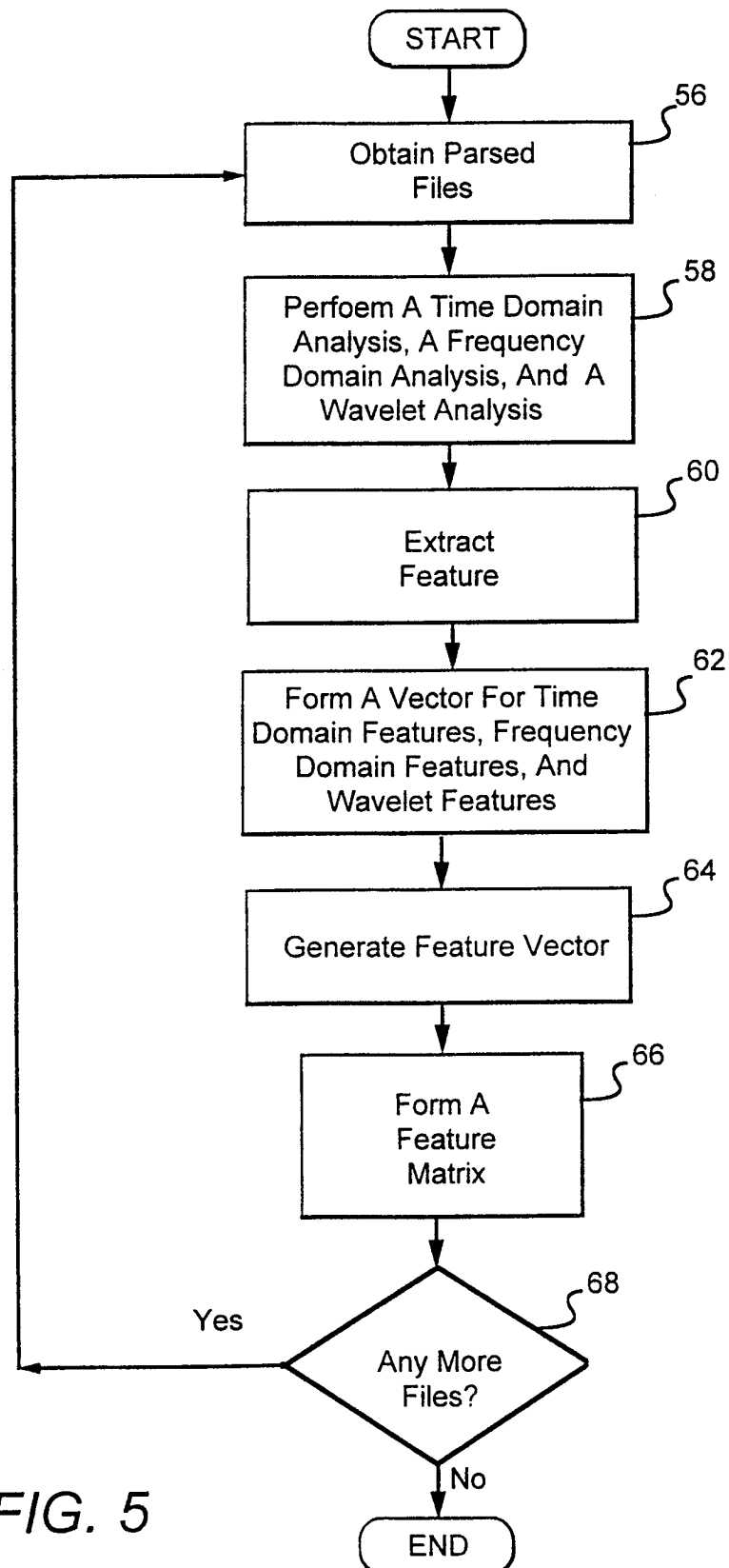


FIG. 5

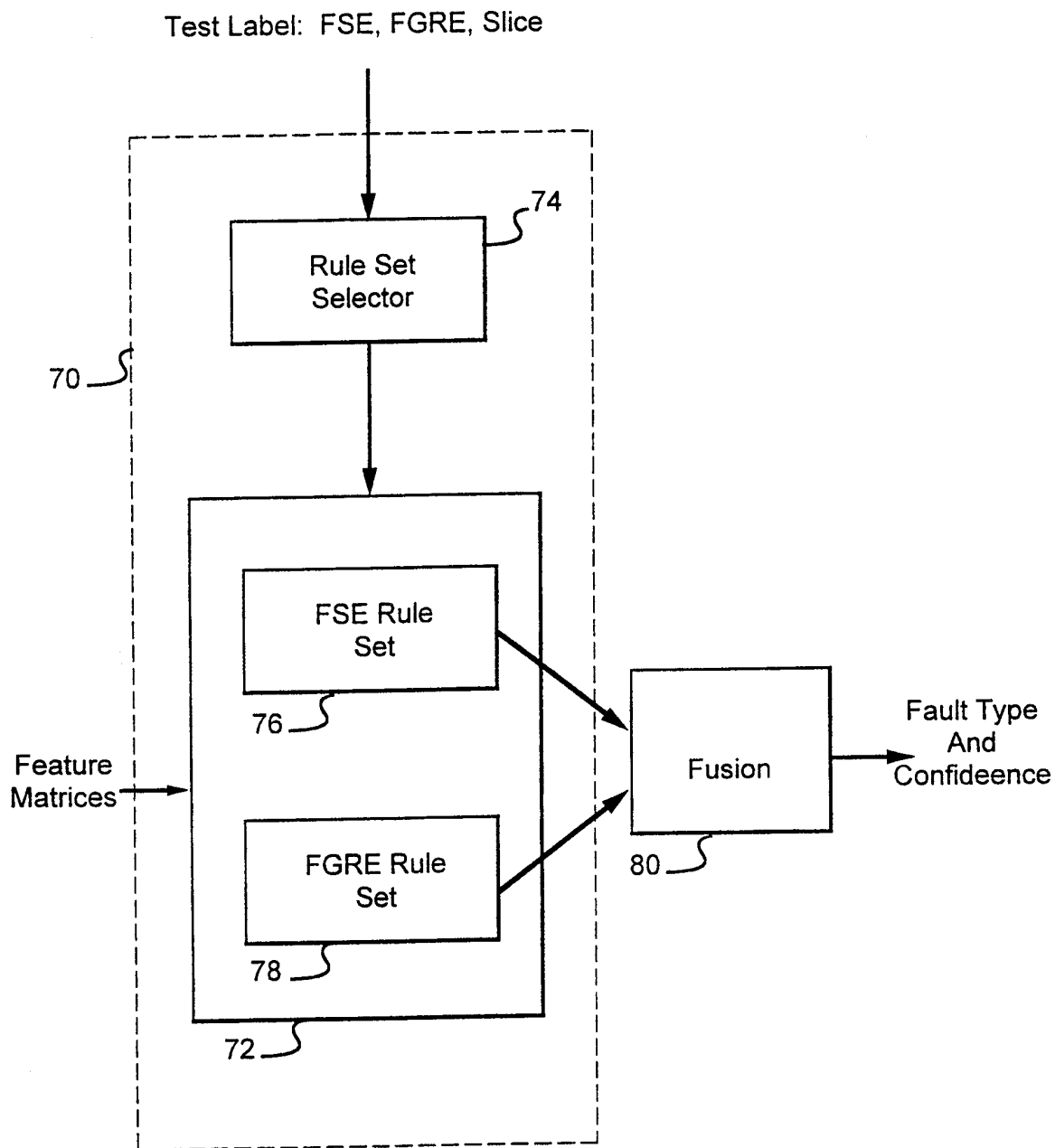


FIG. 6

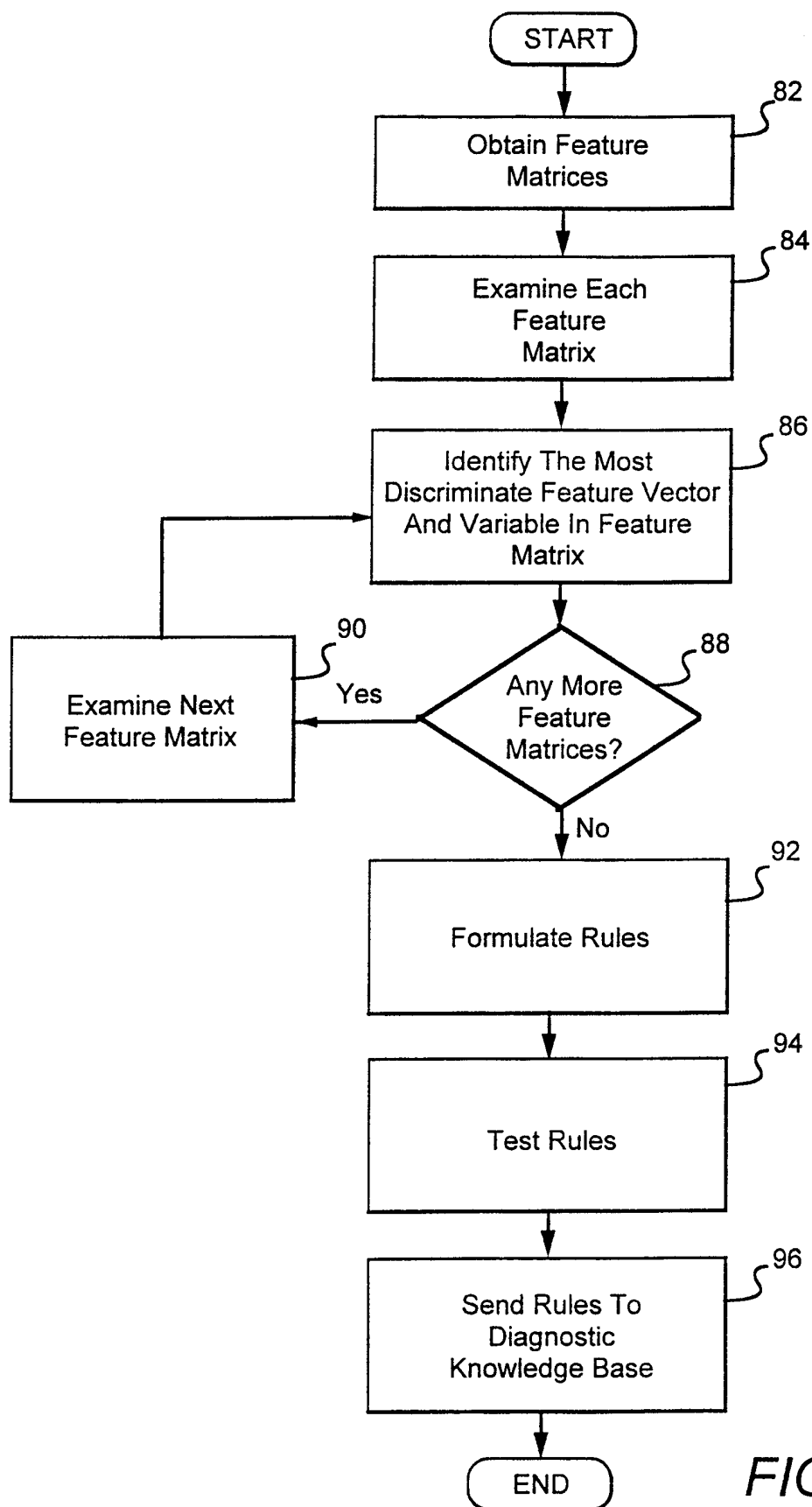
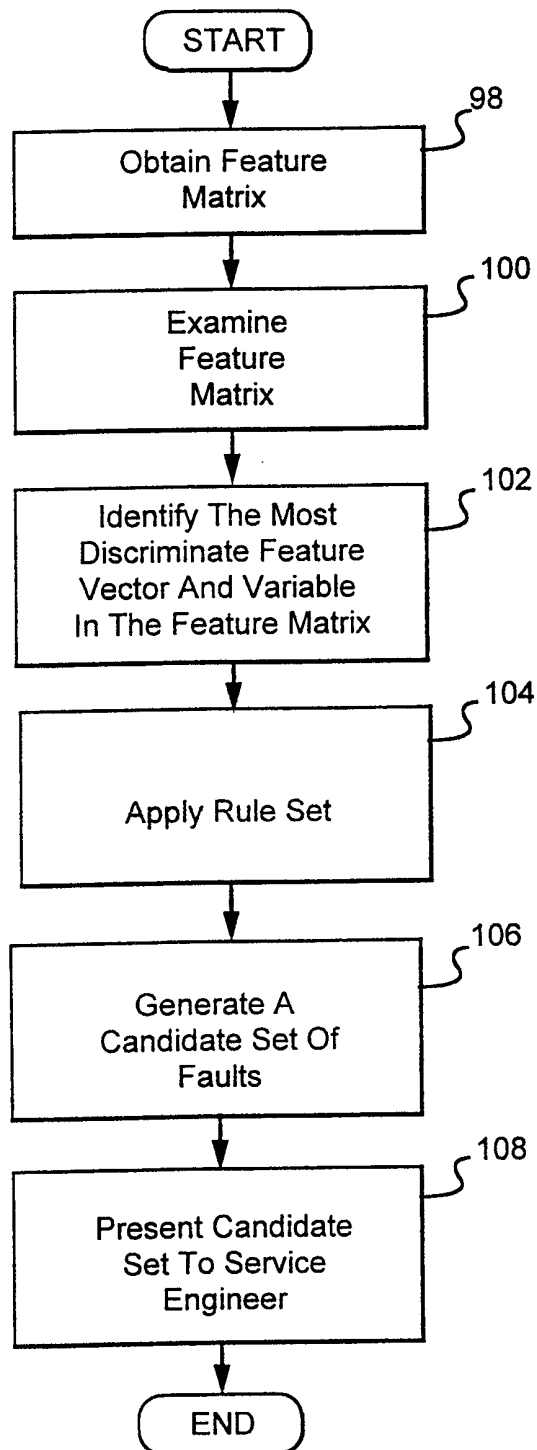


FIG. 7

*FIG. 8*

INTERNATIONAL SEARCH REPORT

International Application No
PCT/US 99/07103

A. CLASSIFICATION OF SUBJECT MATTER
IPC 6 G06F11/22 G06T1/00

According to International Patent Classification (IPC) or to both national classification and IPC

B. FIELDS SEARCHED

Minimum documentation searched (classification system followed by classification symbols)
IPC 6 G06F G01R A61B

Documentation searched other than minimum documentation to the extent that such documents are included in the fields searched

Electronic data base consulted during the international search (name of data base and, where practical, search terms used)

C. DOCUMENTS CONSIDERED TO BE RELEVANT

Category *	Citation of document, with indication, where appropriate, of the relevant passages	Relevant to claim No.
X	MUFTI M ET AL: "AUTOMATED FAULT DETECTION AND IDENTIFICATION USING A FUZZY-WAVELET ANALYSIS TECHNIQUE" CONFERENCE RECORD AUTOTESTCON '95, ATLANTA, AUG. 8 - 10, 1995, no. CONF. 31, 8 August 1995 (1995-08-08), pages 169-175, XP000555102 INSTITUTE OF ELECTRICAL AND ELECTRONICS ENGINEERS ISBN: 0-7803-2622-9 page 169, paragraph 1 - page 172, last paragraph ----	1-6, 12-18, 23-33
X	US 5 463 768 A (CUDDIHY PAUL E ET AL) 31 October 1995 (1995-10-31) column 3, line 30 - column 8, line 55 ----- -/--	1,13,24, 29

☒ Further documents are listed in the continuation of box C.

☒ Patent family members are listed in annex.

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"&" document member of the same patent family

Date of the actual completion of the international search

26 July 1999

Date of mailing of the international search report

03/08/1999

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INTERNATIONAL SEARCH REPORT

International Application No
PCT/US 99/07103

C.(Continuation) DOCUMENTS CONSIDERED TO BE RELEVANT

Category	Citation of document, with indication, where appropriate, of the relevant passages	Relevant to claim No.
P, X	DE 198 29 640 A (GEN ELECTRIC) 4 March 1999 (1999-03-04) page 2, line 63 - page 5, line 61 -----	1, 13, 24, 29

INTERNATIONAL SEARCH REPORT

Information on patent family members

International Application No

PCT/US 99/07103

Patent document cited in search report	Publication date	Patent family member(s)	Publication date
US 5463768 A	31-10-1995	NONE	
DE 19829640 A	04-03-1999	AU 8189598 A NL 1009997 A	18-03-1999 04-03-1999